DEC Chip Design Contest

An improved locking-time PLL with linearized PFD for reducing Cycle-slipping

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Introduction

- Phase-frequency detections (PFD) plays a crucial role in PLL design to detect the phase difference between reference XTAL input and PLL clock.
- However, the conventional PFD, as shown in Fig. 1(a), suffers from non-linear behavior, as depicted in Fig. 1(b), which causes cycle-slipping phenomenon, resulting in delay the locking state of the PLL.



 To improve the PLL locking time, a linearized PFD is proposed in Fig. 1(c) where additional pairs of UP and DN signals are controlled by the state machine illustrated in Fig. 2.

 The following block of PFD, i.e. charge pump (CP) receives the UP and DN signals and generates a linearized l_{out} proportional to the phase difference, overcoming the cycle-slipping issue.



- The micro-photograph of the proposed PLL is shown in Fig. 3, covering an area of 0.95 mm².
- Fig. 4(a) exhibits a locking-time achieving 3.6 us while the phase noise is measured -98.9 dBc at 1 MHz. The proposed PLL performances are shown and compared with other works in Table I.

Conclusion

- The non-ideal behavior of conventional PFD degrades the locking-time specification of PLL.
- To overcome the bottleneck, a linearized PFD is proposed to improve locking-time of PLL while achieving good phase noise with low power consumption.

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